



LR013N10SM10

N-MOSFET TOLL 100V, 330A, 1.1mΩ

Features

- Uses advanced SGT technology
- Extremely low on-resistance $R_{DS(on)}$
- Excellent gate charge x $R_{DS(on)}$ product(FOM)

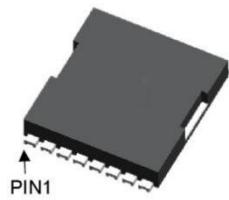
Application

- Motor control and drives
- Battery management
- DC/DC converter
- General purpose applications

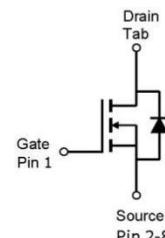
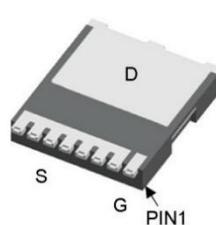
Product Summary

V_{DS}	100V
$R_{DS(on)}@VGS=10V$	1.1mΩ
I_D	330A

TOLL Top View



TOLL Bottom View

**Package Marking and Ordering Information**

Type	Package	Marking	Reel Size	Tape Width	Qty
LR013N10SM10	TOLL	LR013N10SM10	330*28.5mm	24mm	2000

Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	100	V
Continuous drain current $T_C = 25^\circ C$ (Silicon limit) $T_C = 100^\circ C$ (Silicon limit)	I_D	330	A
$T_C = 25^\circ C$, t_p limited by T_{jmax}		248	
Pulsed drain current $T_C = 25^\circ C$, t_p limited by T_{jmax}	$I_{D \text{ pulse}}$	1320	
Avalanche energy, single pulse ($L=0.3\text{mH}, R_g=25\Omega$) ⁽¹⁾	E_{AS}	1750	mJ
Gate-Source voltage	V_{GS}	± 20	V
Power dissipation $T_C = 25^\circ C$	P_D	431	W
Operating junction and storage temperature	T_j, T_{stg}	-55~150	°C

Notes:(1) $V_{DS}=75V, V_{GS}=10V, L=0.3\text{mH}$.

**Thermal Resistance**

	Symbol	Value	Unit
Thermal resistance, junction – case. Max	R_{thJC}	0.29	°C/W

Electrical Characteristic, at $T_j = 25$ °C, unless otherwise specified

Parameter	Symbol	Test Condition	Value			Unit
			min.	typ.	max.	

Static Characteristic

Drain-source breakdown voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=250\mu A$	100	-	-	V
Gate threshold voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$ $T_j=25^\circ C$	2.2	2.6	3.8	
Zero gate voltage drain current	I_{DSS}	$V_{DS}=100V, V_{GS}=0V$ $T_j=25^\circ C$	-	-	1	μA
Gate-source leakage current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	± 100	nA
Drain-source on-state resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=100A,$ $T_j=25^\circ C$	-	1.05	1.3	$m\Omega$
Transconductance	g_{fs}	$V_{DS}=5V, I_D=100A$	-	280	-	S

Dynamic Characteristic

Input Capacitance	C_{iss}	$V_{GS}=0V, V_{DS}=50V,$ $f=1MHz$	-	15650	-	pF
Output Capacitance	C_{oss}		-	2100	-	
Reverse Transfer Capacitance	C_{rss}		-	80	-	
Gate Total Charge	Q_G	$V_{GS}=10V, V_{DS}=50V,$ $I_D=100A$	-	258	-	nC
Gate-Source charge	Q_{gs}		-	68	-	
Gate-Drain charge	Q_{gd}		-	74	-	
Turn-on delay time	$t_{d(on)}$	$I_D=100A, V_{GS}=10V,$ $V_{DS}=50V, R_G=3\Omega$	-	28	-	ns
Rise time	t_r		-	73	-	
Turn-off delay time	$t_{d(off)}$		-	86	-	
Fall time	t_f		-	33	-	
Gate resistance	R_G	$V_{GS}=0V, V_{DS}=0V,$ $f=1MHz$	-	1	-	Ω

Body Diode Characteristic

Body Diode Forward Voltage	V_{SD}	$V_{GS}=0V, I_{SD}=100A$	-	0.8	1.1	V
Body Diode Reverse Recovery Time	t_{rr}	$I_F=100A,$ $dI/dt=100A/\mu s$	-	115	-	ns
Body Diode Reverse Recovery Charge	Q_{rr}	$I_F=100A,$ $dI/dt=100A/\mu s$	-	320	-	nC



Typical Performance Characteristics

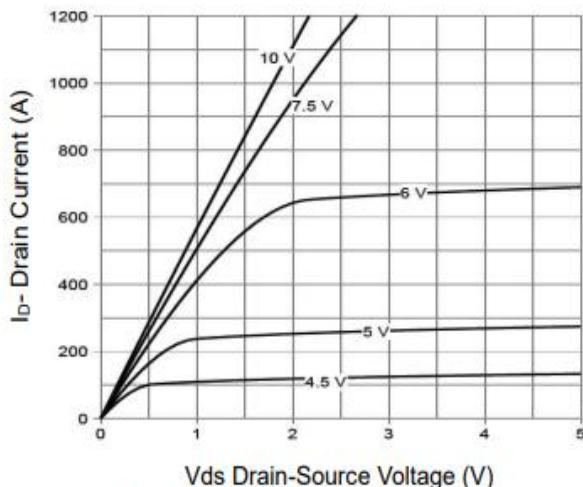


Figure 1 Output Characteristics

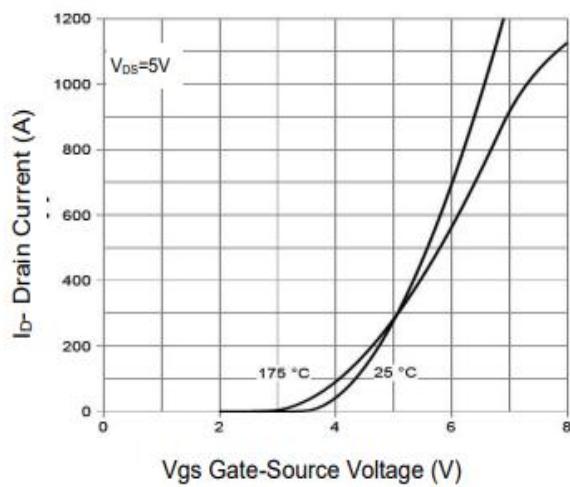


Figure 2 Transfer Characteristics

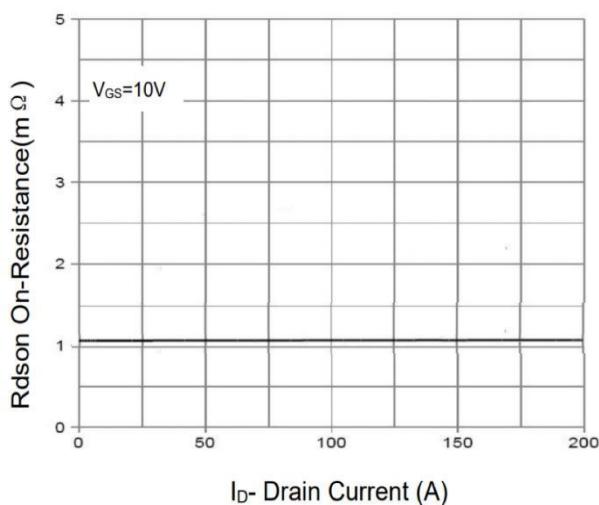


Figure 3 Rdson- Drain Current

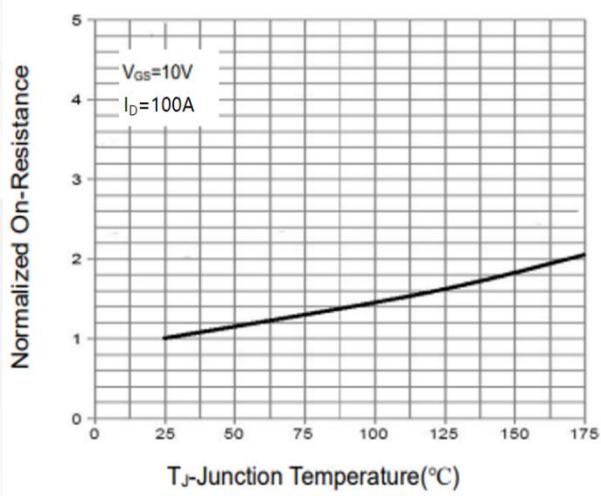


Figure 4 Rdson-Junction Temperature

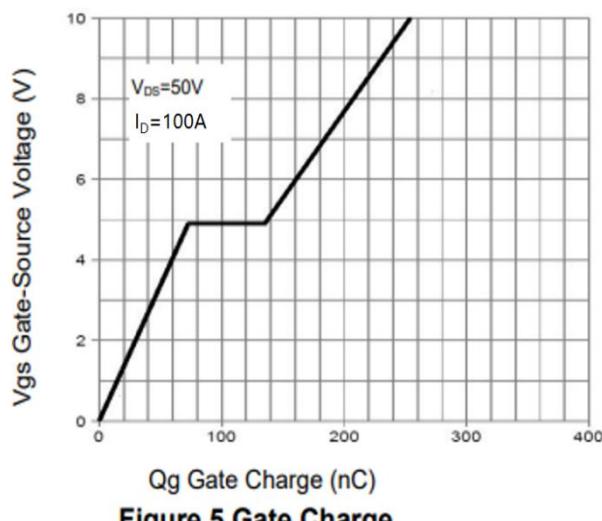


Figure 5 Gate Charge

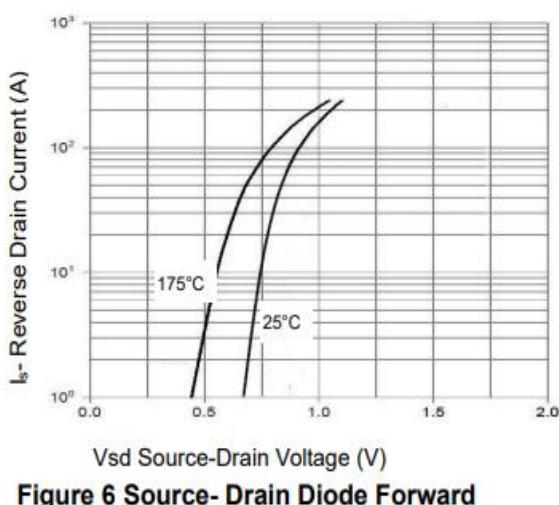


Figure 6 Source- Drain Diode Forward

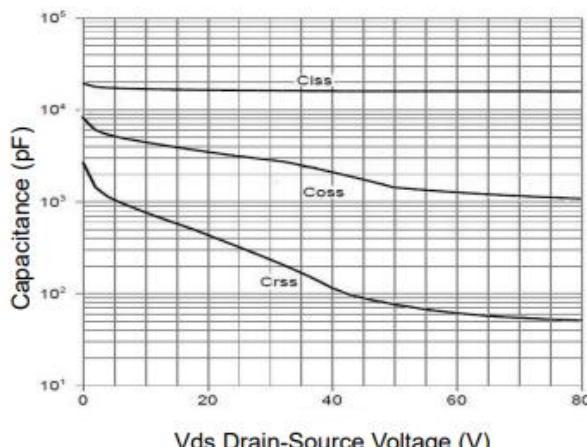


Figure 7 Capacitance vs Vds

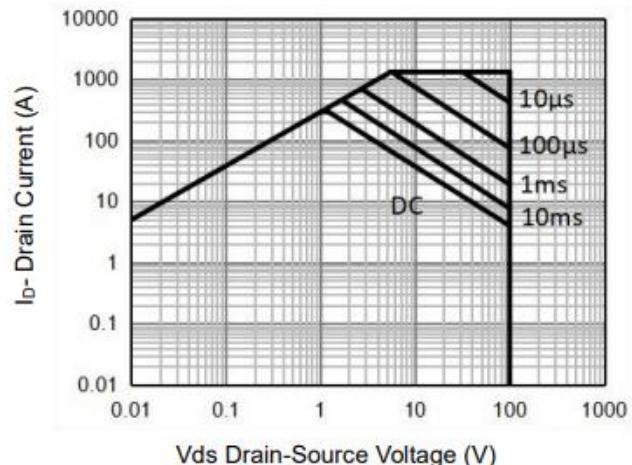


Figure 8 Safe Operation Area^(Note 3)

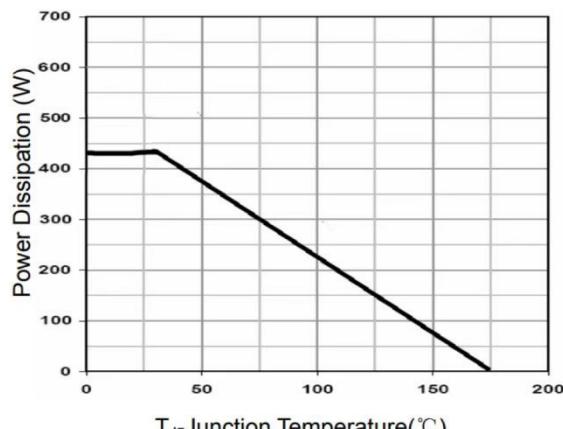


Figure 9 Power De-rating

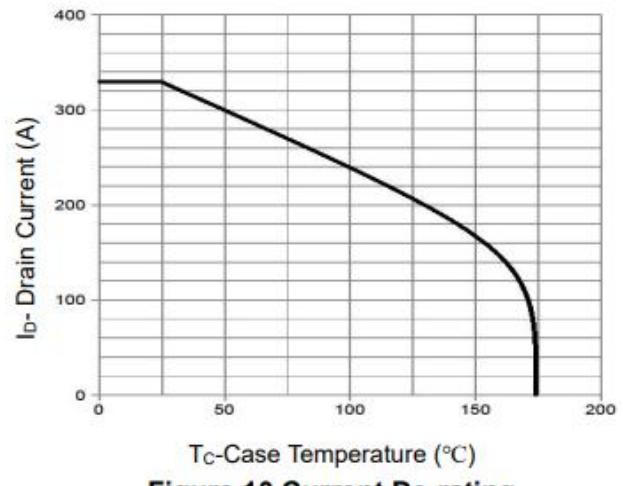


Figure 10 Current De-rating

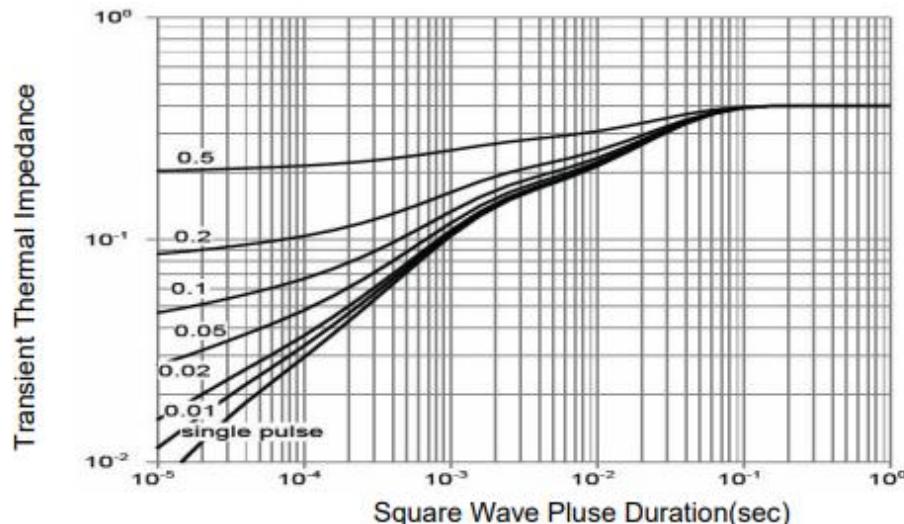
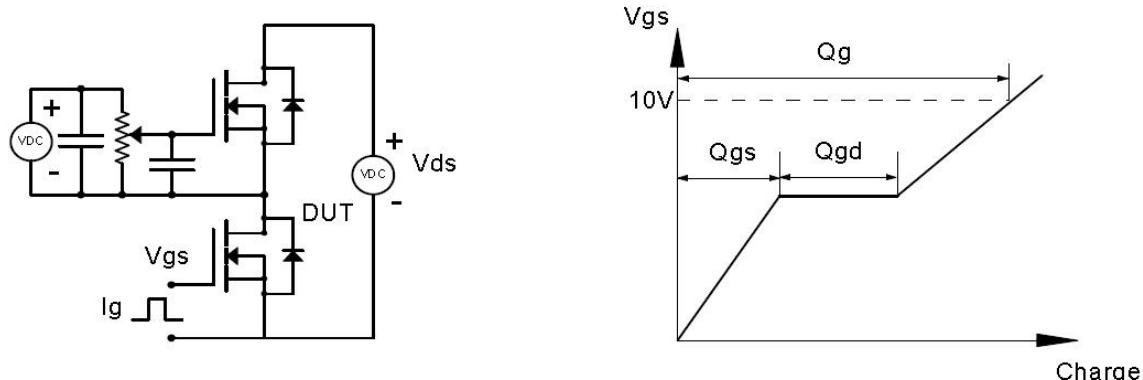


Figure 11 Normalized Maximum Transient Thermal Impedance

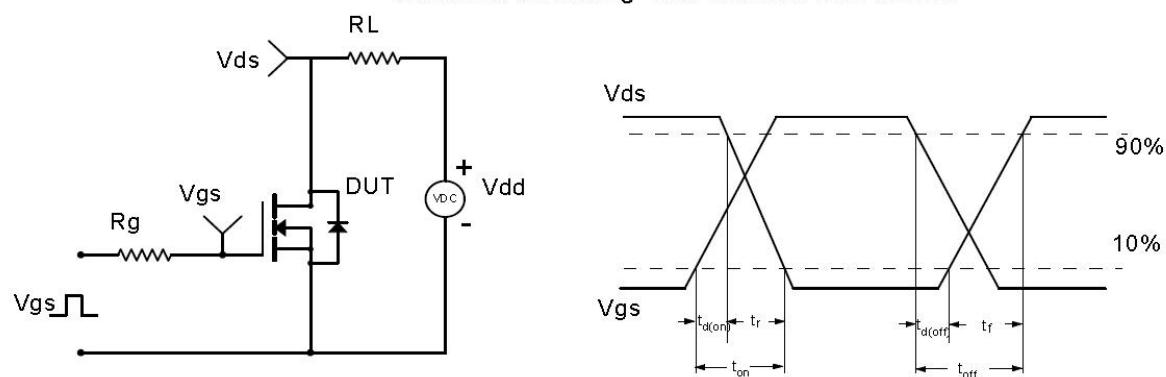


Test Circuit & Waveform

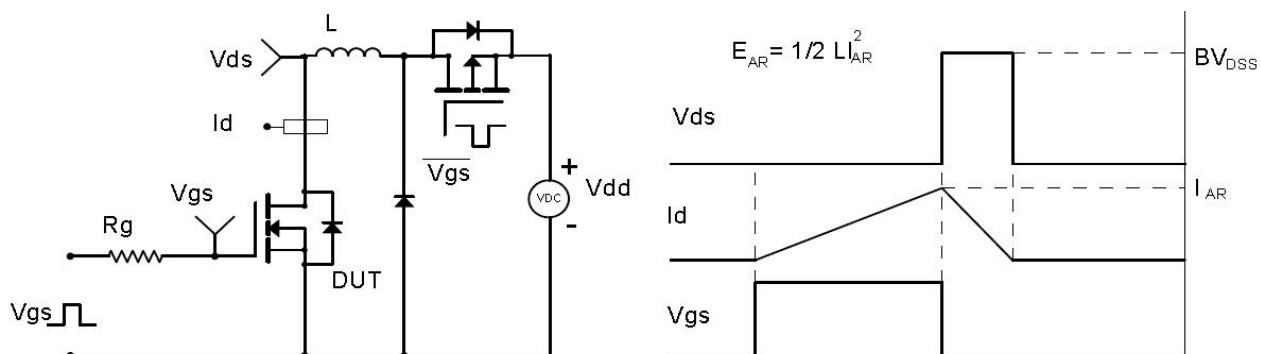
Gate Charge Test Circuit & Waveform



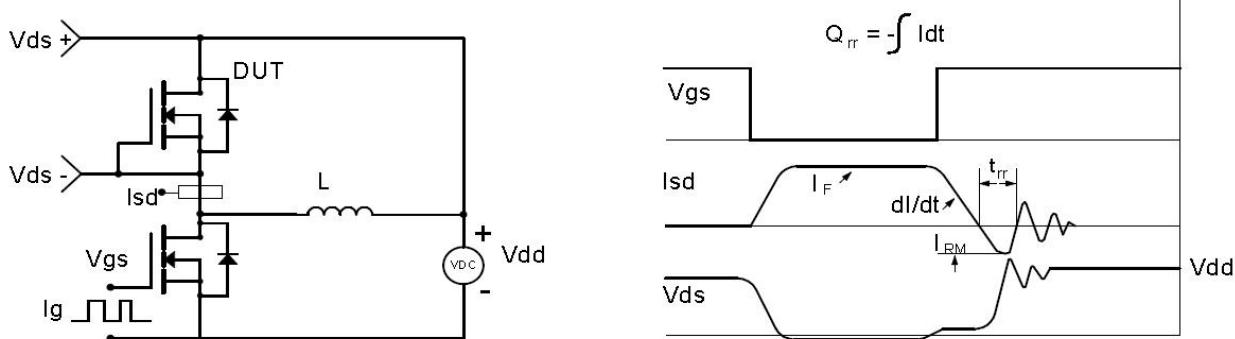
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms





Package Outline: DFN5X6

